

# International IR Rectifier

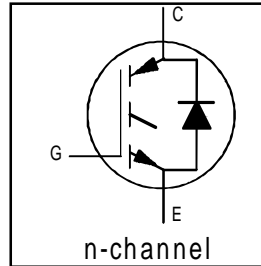
PD - 94255

## INSULATED GATE BIPOLAR TRANSISTOR WITH ULTRAFAST SOFT RECOVERY DIODE

## IRG4BC10SD-S IRG4BC10SD-L Standard Speed CoPack IGBT

### Features

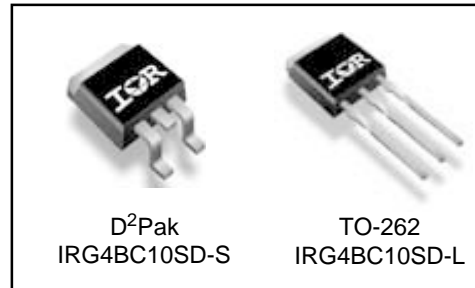
- Extremely low voltage drop 1.1Vtyp. @ 2A
- S-Series: Minimizes power dissipation at up to 3 KHz PWM frequency in inverter drives, up to 4 KHz in brushless DC drives.
- Very Tight Vce(on) distribution
- IGBT co-packaged with HEXFRED™ ultrafast, ultra-soft-recovery anti-parallel diodes for use in bridge configurations
- Industry standard D<sup>2</sup>Pak & TO-262 packages



$V_{CES} = 600V$
$V_{CE(on)} \text{ typ.} = 1.10V$
@ $V_{GE} = 15V, I_C = 2.0A$

### Benefits

- Generation 4 IGBT's offer highest efficiencies available
- IGBT's optimized for specific application conditions
- HEXFRED diodes optimized for performance with IGBT's. Minimized recovery characteristics require less/no snubbing
- Lower losses than MOSFET's conduction and Diode losses



D<sup>2</sup>Pak  
IRG4BC10SD-S

TO-262  
IRG4BC10SD-L

### Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{CES}$	Collector-to-Emitter Voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	14	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	8.0	
$I_{CM}$	Pulsed Collector Current ①	18	
$I_{LM}$	Clamped Inductive Load Current ②	18	
$I_F @ T_C = 100^\circ C$	Diode Continuous Forward Current	4.0	
$I_{FM}$	Diode Maximum Forward Current	18	
$V_{GE}$	Gate-to-Emitter Voltage	$\pm 20$	V
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	38	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	15	
$T_J$	Operating Junction and	-55 to +150	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case - IGBT	—	—	3.3	°C/W
$R_{\theta JC}$	Junction-to-Case - Diode	—	—	7.0	
$R_{\theta CS}$	Case-to-Sink, flat, greased surface	—	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient, typical socket mount ⑤	—	—	80	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state)⑥	—	—	40	
Wt	Weight	—	2.0(0.07)	—	

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# IRG4BC10SD-S/L

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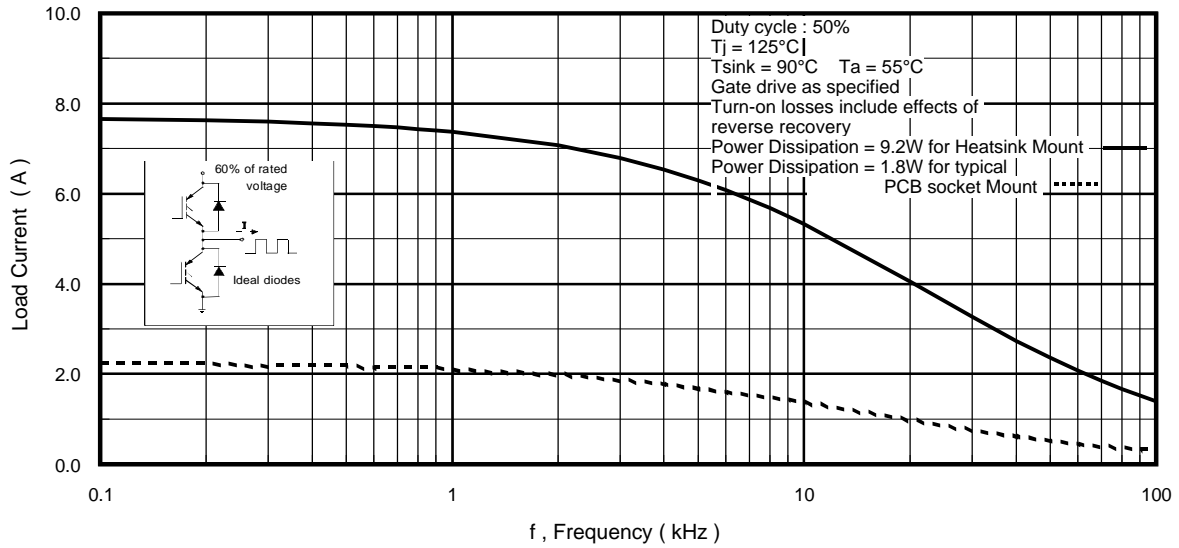
## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage <sup>③</sup>	600	—	—	V	$V_{GE} = 0V, I_C = 250\mu A$
$\Delta V_{(BR)CES}/\Delta T_J$	Temperature Coeff. of Breakdown Voltage	—	0.64	—	V/°C	$V_{GE} = 0V, I_C = 1.0mA$
$V_{CE(on)}$	Collector-to-Emitter Saturation Voltage	—	1.58	1.8	V	$I_C = 8.0A$ $I_C = 14.0A$ $I_C = 8.0A, T_J = 150^\circ\text{C}$ $V_{GE} = 15V$ See Fig. 2, 5
		—	2.05	—		
		—	1.68	—		
$V_{GE(th)}$	Gate Threshold Voltage	3.0	—	6.0		$V_{CE} = V_{GE}, I_C = 250\mu A$
$\Delta V_{GE(th)}/\Delta T_J$	Temperature Coeff. of Threshold Voltage	—	-9.5	—	mV/°C	$V_{CE} = V_{GE}, I_C = 250\mu A$
$g_{fe}$	Forward Transconductance <sup>④</sup>	3.65	5.48	—	S	$V_{CE} = 100V, I_C = 8.0A$
$I_{CES}$	Zero Gate Voltage Collector Current	—	—	250	$\mu A$	$V_{GE} = 0V, V_{CE} = 600V$ $V_{GE} = 0V, V_{CE} = 600V, T_J = 150^\circ\text{C}$
		—	—	1000		
$V_{FM}$	Diode Forward Voltage Drop	—	1.5	1.8	V	$I_C = 4.0A$ $I_C = 4.0A, T_J = 150^\circ\text{C}$ See Fig. 13
		—	1.4	1.7		
$I_{GES}$	Gate-to-Emitter Leakage Current	—	—	$\pm 100$	nA	$V_{GE} = \pm 20V$

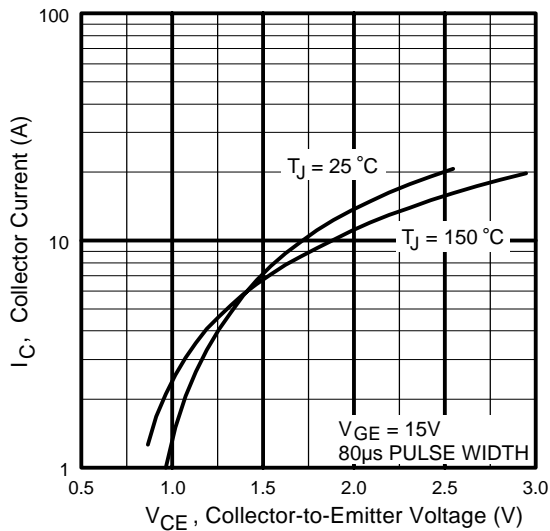
## Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions	
$Q_g$	Total Gate Charge (turn-on)	—	15	22	nC	$I_C = 8.0A$ $V_{CC} = 400V$ $V_{GE} = 15V$ See Fig. 8	
$Q_{ge}$	Gate - Emitter Charge (turn-on)	—	2.42	3.6			
$Q_{gc}$	Gate - Collector Charge (turn-on)	—	6.53	9.8			
$t_{d(on)}$	Turn-On Delay Time	—	76	—	ns	$T_J = 25^\circ\text{C}$ $I_C = 8.0A, V_{CC} = 480V$ $V_{GE} = 15V, R_G = 100\Omega$ Energy losses include "tail" and diode reverse recovery. See Fig. 9, 10, 18	
$t_r$	Rise Time	—	32	—			
$t_{d(off)}$	Turn-Off Delay Time	—	815	1200			
$t_f$	Fall Time	—	720	1080			
$E_{on}$	Turn-On Switching Loss	—	0.31	—			
$E_{off}$	Turn-Off Switching Loss	—	3.28	—	mJ		
$E_{ts}$	Total Switching Loss	—	3.60	10.9			
$E_{ts}$	Total Switching Loss	—	1.46	2.6	mJ	$I_C = 5.0A$	
$t_{d(on)}$	Turn-On Delay Time	—	70	—	ns	$T_J = 150^\circ\text{C}$ , See Fig. 10,11, 18 $I_C = 8.0A, V_{CC} = 480V$ $V_{GE} = 15V, R_G = 100\Omega$ Energy losses include "tail" and diode reverse recovery.	
$t_r$	Rise Time	—	36	—			
$t_{d(off)}$	Turn-Off Delay Time	—	890	—			
$t_f$	Fall Time	—	890	—			
$E_{ts}$	Total Switching Loss	—	3.83	—	mJ		
$L_E$	Internal Emitter Inductance	—	7.5	—	nH	Measured 5mm from package	
$C_{ies}$	Input Capacitance	—	280	—	pF	$V_{GE} = 0V$ $V_{CC} = 30V$ $f = 1.0MHz$ See Fig. 7	
$C_{oes}$	Output Capacitance	—	30	—			
$C_{res}$	Reverse Transfer Capacitance	—	4.0	—			
$t_{rr}$	Diode Reverse Recovery Time	—	28	42	ns	$T_J = 25^\circ\text{C}$ See Fig. 14 $T_J = 125^\circ\text{C}$	$I_F = 4.0A$ $V_R = 200V$ $di/dt = 200A/\mu s$
		—	38	57			
$I_{rr}$	Diode Peak Reverse Recovery Current	—	2.9	5.2	A	$T_J = 25^\circ\text{C}$ See Fig. 15 $T_J = 125^\circ\text{C}$	
		—	3.7	6.7			
$Q_{rr}$	Diode Reverse Recovery Charge	—	40	60	nC	$T_J = 25^\circ\text{C}$ See Fig. 16 $T_J = 125^\circ\text{C}$	
		—	70	105			
$di_{(rec)M}/dt$	Diode Peak Rate of Fall of Recovery During $t_b$	—	280	—	A/ $\mu s$	$T_J = 25^\circ\text{C}$ See Fig. 17 $T_J = 125^\circ\text{C}$	
		—	235	—			

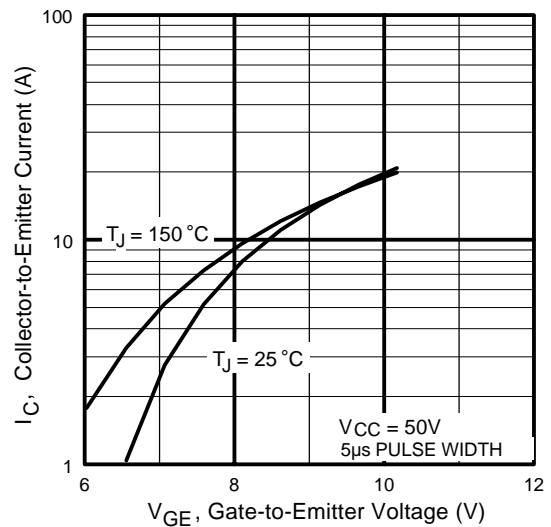
Details of note ① through ④ are on the last page



**Fig. 1 - Typical Load Current vs. Frequency**  
 (Load Current =  $I_{\text{RMS}}$  of fundamental)

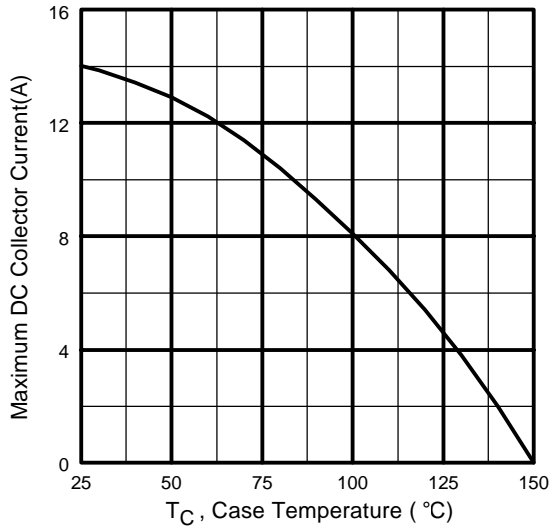


**Fig. 2 - Typical Output Characteristics**

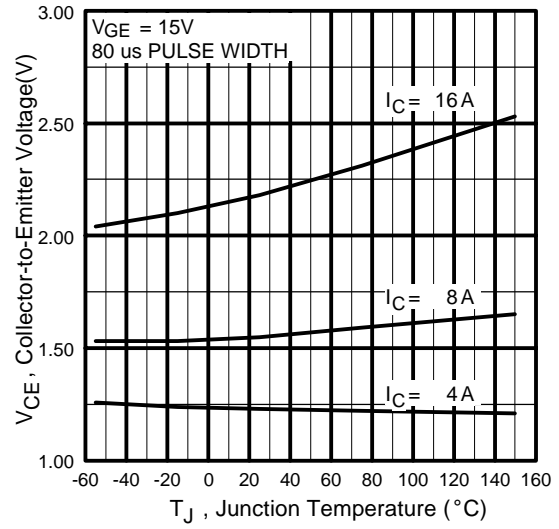


**Fig. 3 - Typical Transfer Characteristics**

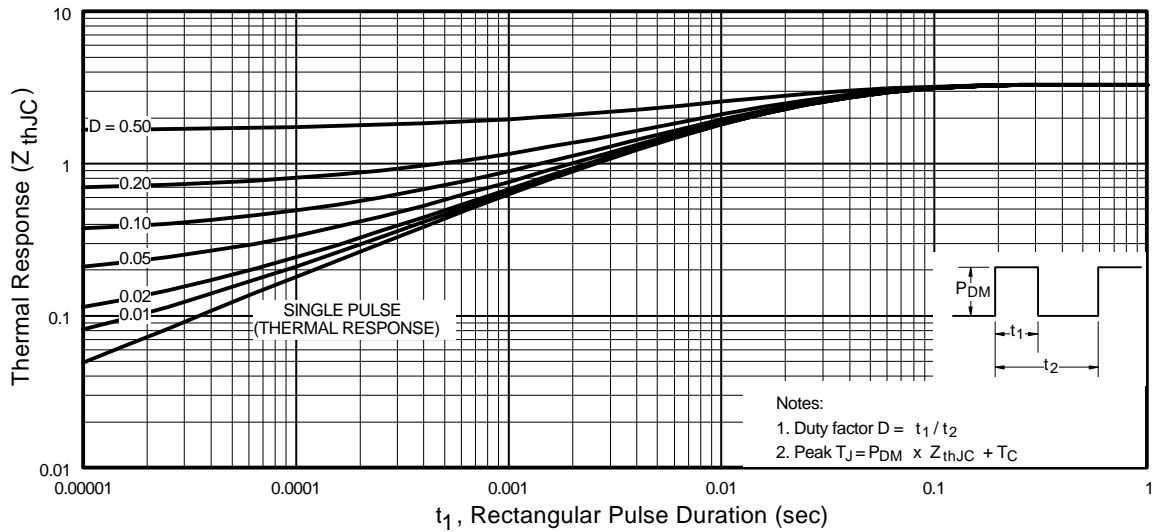
# IRG4BC10SD-S/L



**Fig. 4** - Maximum Collector Current vs. Case Temperature

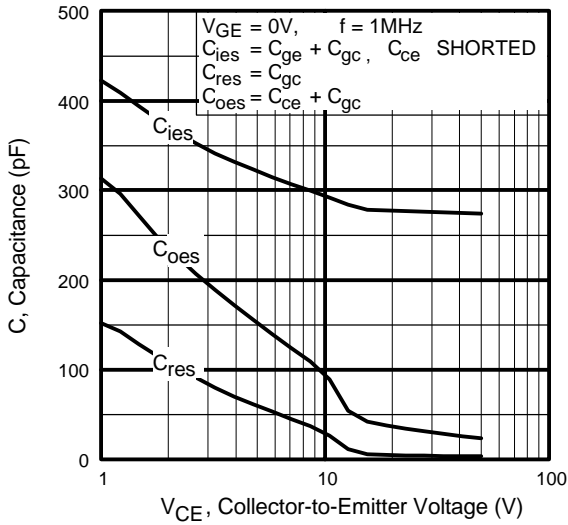


**Fig. 5** - Typical Collector-to-Emitter Voltage vs. Junction Temperature

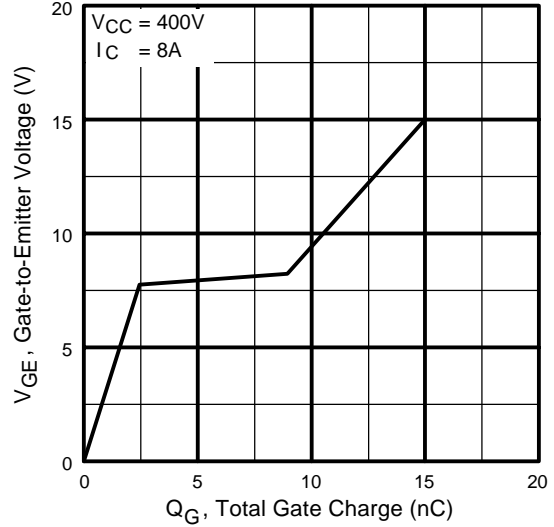


**Fig. 6** - Maximum Effective Transient Thermal Impedance, Junction-to-Case

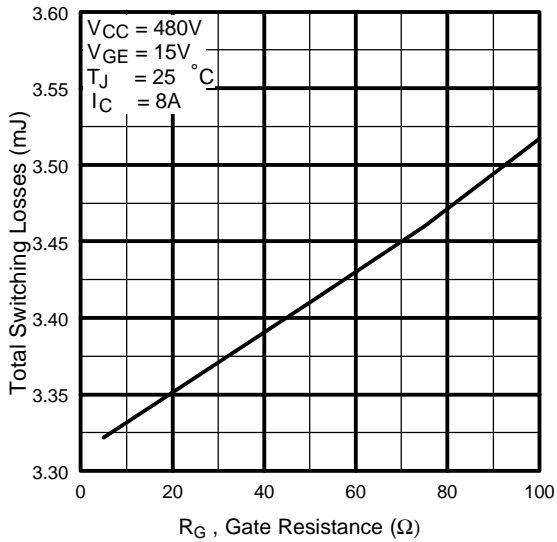
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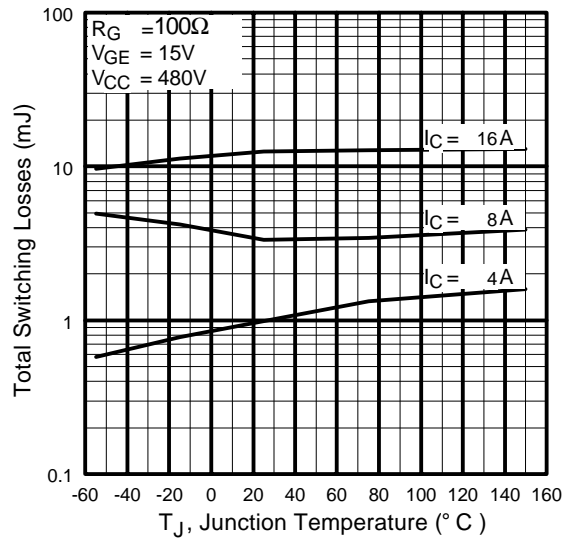
**Fig. 7** - Typical Capacitance vs. Collector-to-Emitter Voltage



**Fig. 8** - Typical Gate Charge vs. Gate-to-Emitter Voltage



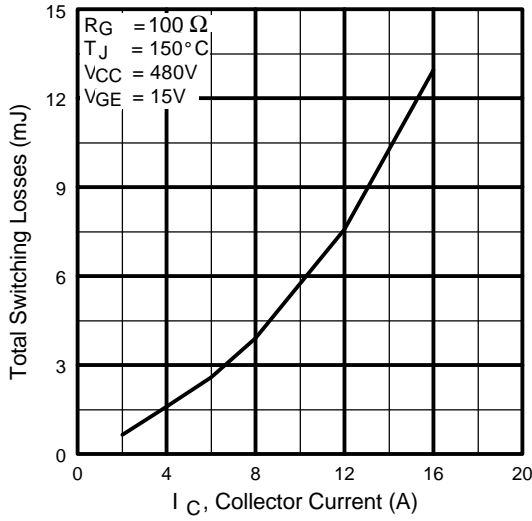
**Fig. 9** - Typical Switching Losses vs. Gate Resistance



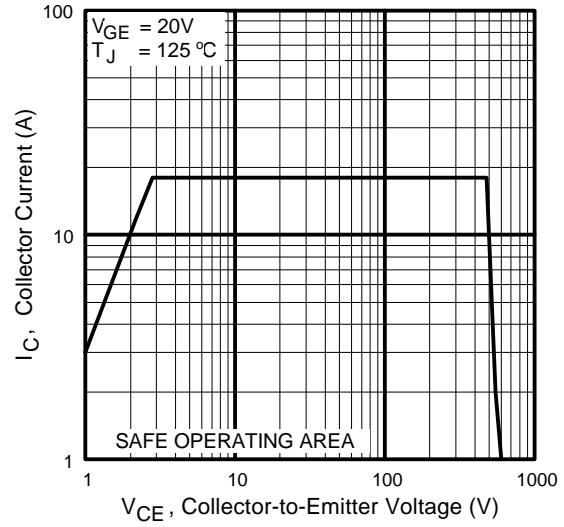
**Fig. 10** - Typical Switching Losses vs. Junction Temperature

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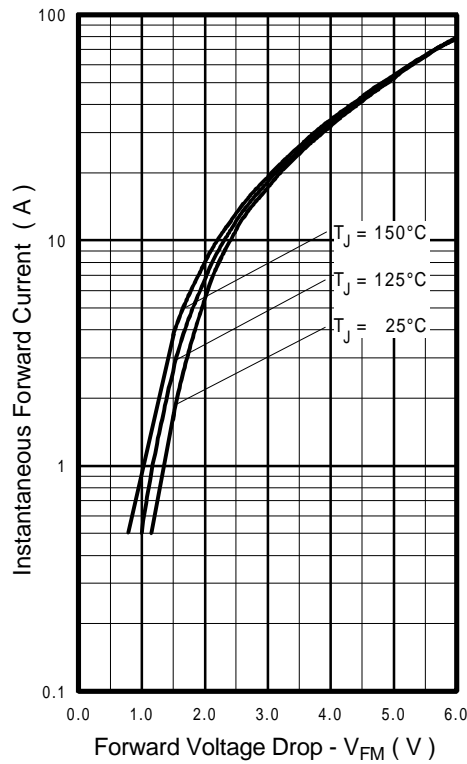
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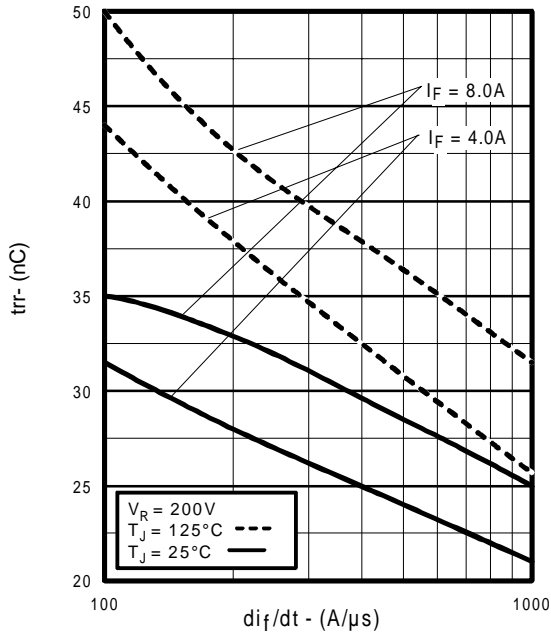
**Fig. 11** - Typical Switching Losses vs. Collector Current



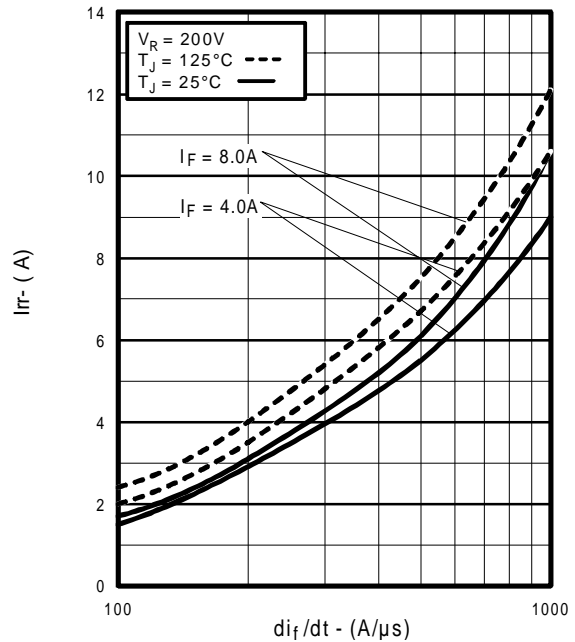
**Fig. 12** - Turn-Off SOA



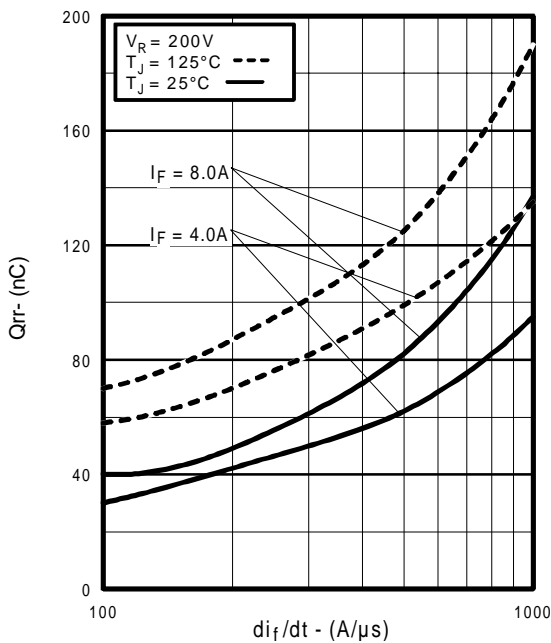
**Fig. 13** - Maximum Forward Voltage Drop vs. Instantaneous Forward Current



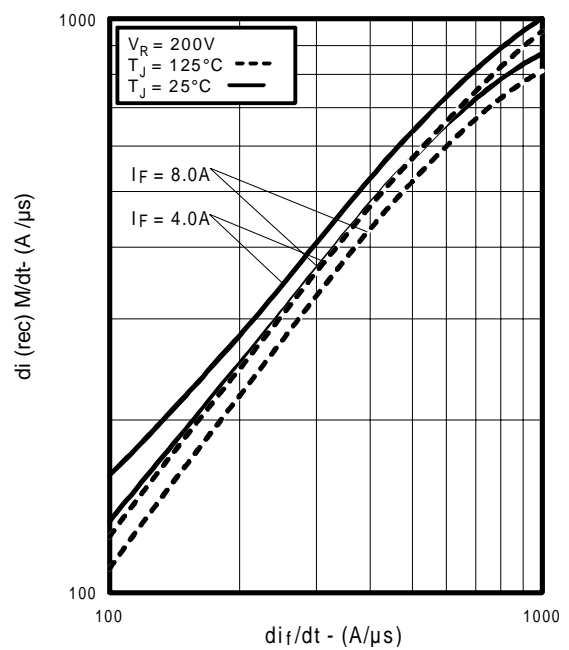
**Fig. 14** - Typical Reverse Recovery vs.  $dI_f/dt$



**Fig. 15** - Typical Recovery Current vs.  $dI_f/dt$

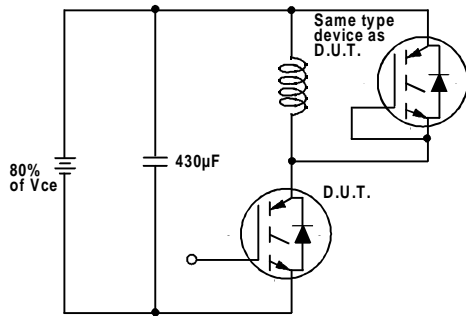


**Fig. 16** - Typical Stored Charge vs.  $dI_f/dt$

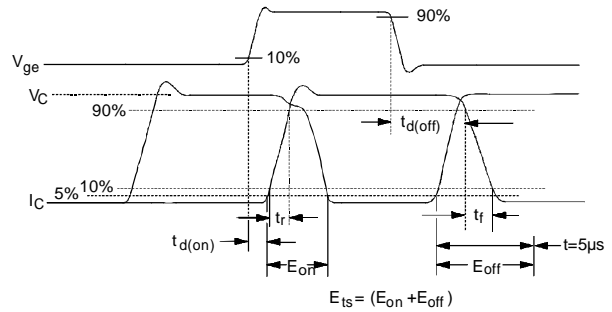


**Fig. 17** - Typical  $dI_{(rec)M}/dt$  vs.  $dI_f/dt$ ,

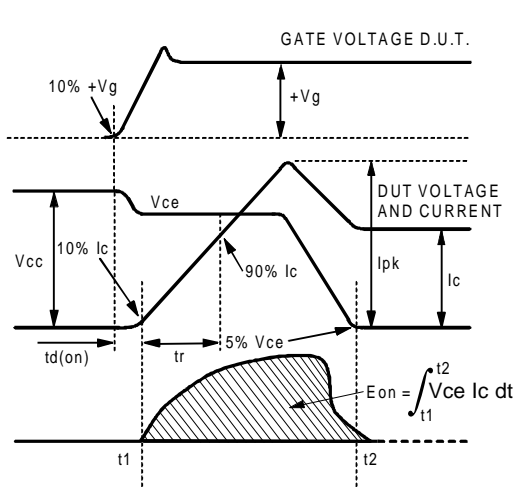
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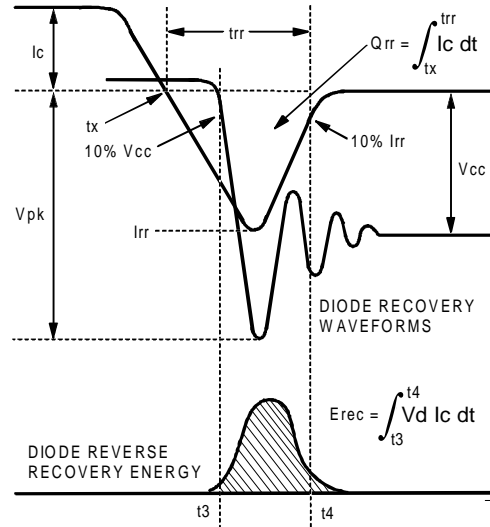
**Fig. 18a** - Test Circuit for Measurement of  $I_{LM}$ ,  $E_{on}$ ,  $E_{off}(\text{diode})$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$ ,  $t_{d(on)}$ ,  $t_r$ ,  $t_{d(off)}$ ,  $t_f$



**Fig. 18b** - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{off}$ ,  $t_{d(off)}$ ,  $t_f$



**Fig. 18c** - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{on}$ ,  $t_{d(on)}$ ,  $t_r$



**Fig. 18d** - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{rec}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$



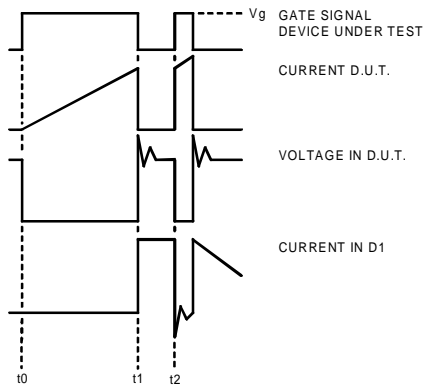


Figure 18e. Macro Waveforms for Figure 18a's Test Circuit

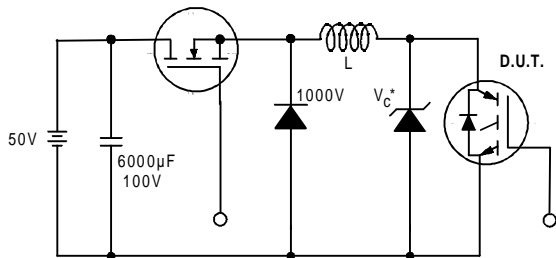


Figure 19. Clamped Inductive Load Test Circuit

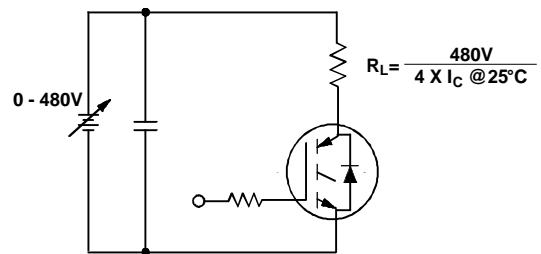
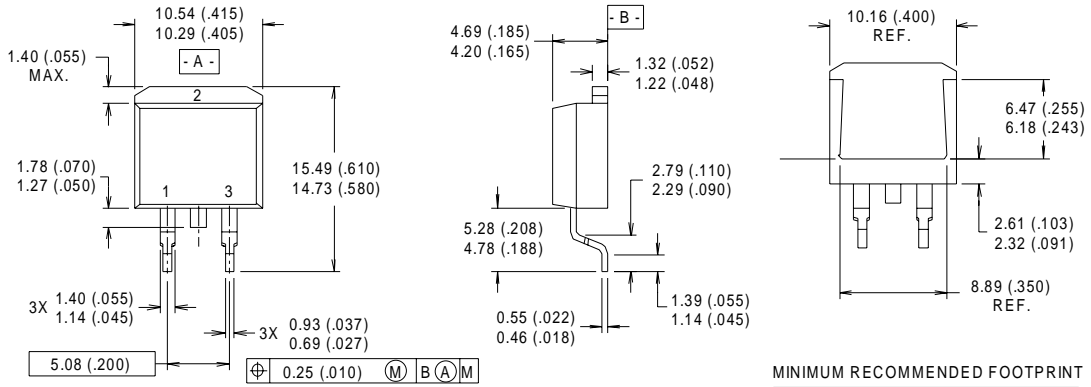


Figure 20. Pulsed Collector Current Test Circuit

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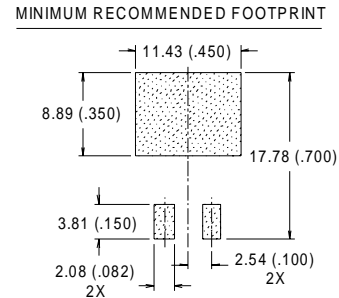


## D<sup>2</sup>Pak Package Outline

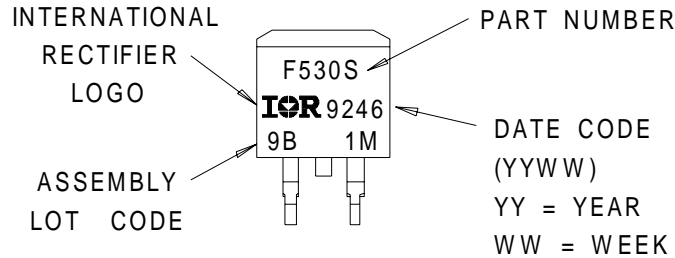


- NOTES:
- 1 DIMENSIONS AFTER SOLDER DIP.
  - 2 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
  - 3 CONTROLLING DIMENSION : INCH.
  - 4 HEATSINK & LEAD DIMENSIONS DO NOT INCLUDE BURRS.

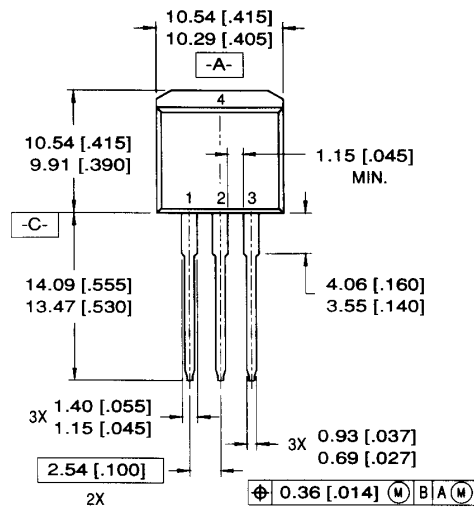
- LEAD ASSIGNMENTS
- 1 - GATE
  - 2 - DRAIN
  - 3 - SOURCE



## D<sup>2</sup>Pak Part Marking Information

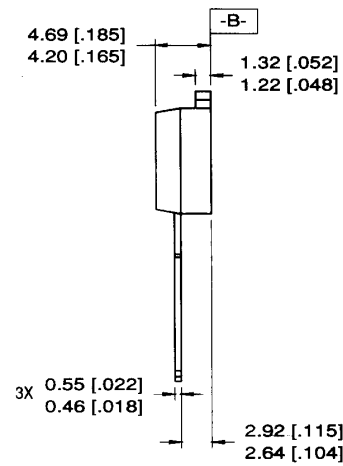


## TO-262 Package Outline



**LEAD ASSIGNMENTS**

- |           |            |
|-----------|------------|
| 1 = GATE  | 3 = SOURCE |
| 2 = DRAIN | 4 = DRAIN  |

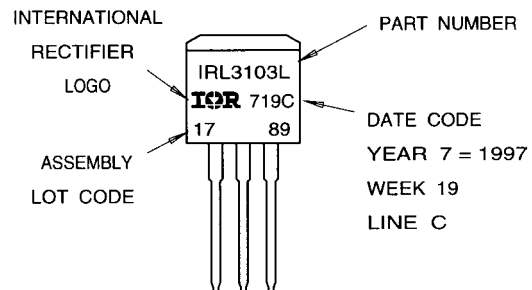


**NOTES:**

1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1982
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. HEATSINK & LEAD DIMENSIONS DO NOT INCLUDE BURRS.

## TO-262 Part Marking Information

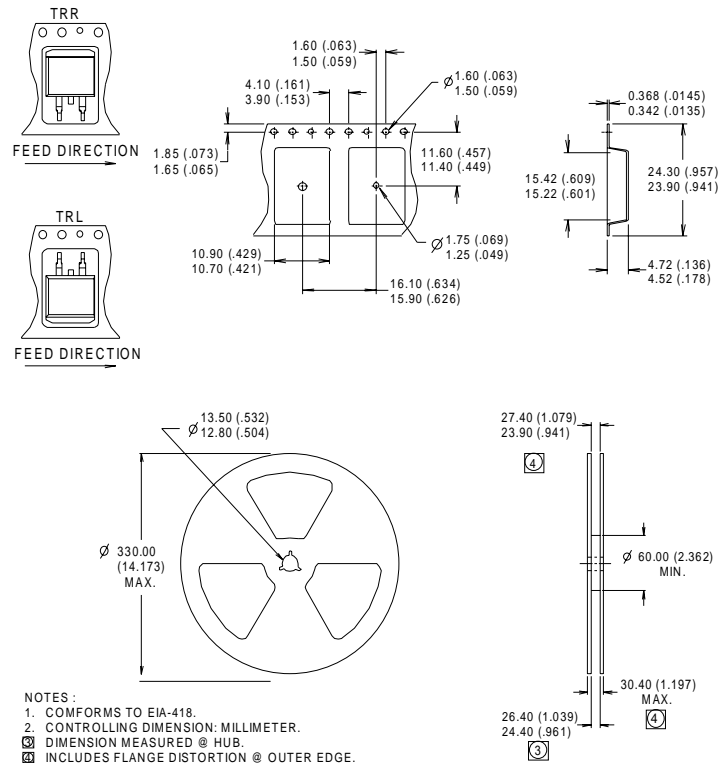
EXAMPLE: THIS IS AN IRL3103L  
 LOT CODE 1789  
 ASSEMBLED ON WW 19, 1997  
 IN THE ASSEMBLY LINE "C"



# IRG4BC10SD-S/L

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## D<sup>2</sup>Pak Tape & Reel Information



### Notes:

- ① Repetitive rating:  $V_{GE}=20V$ ; pulse width limited by maximum junction temperature (figure 20)
- ②  $V_{CC}=80\%(V_{CES})$ ,  $V_{GE}=20V$ ,  $L=10\mu H$ ,  $R_G = 100W$  (figure 19)
- ③ Pulse width  $\leq 80\mu s$ ; duty factor  $\leq 0.1\%$ .
- ④ Pulse width  $5.0\mu s$ , single shot.
- ⑤ This only applies to TO-262 package.
- ⑥ This applies to D<sup>2</sup>Pak, when mounted on 1" square PCB (FR-4 or G-10 Material).  
For recommended footprint and soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice.

This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.

International  
**IR** Rectifier

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Note: For the most current drawings please refer to the IR website at:  
<http://www.irf.com/package/>